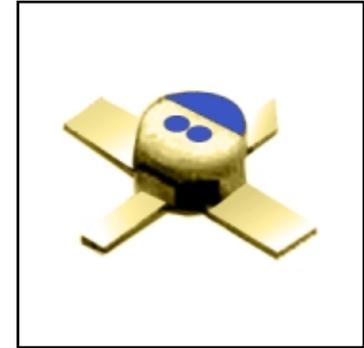


### FEATURES

- High Output Power:  $P_{1dB} = 20.0\text{dBm}$  (Typ.)
- High Associated Gain:  $G_{1dB} = 19.0\text{dB}$  (Typ.)
- Low Noise Figure:  $NF=0.55\text{dB}$  (Typ.) @  $f=2\text{GHz}$
- Low Bias Conditions:  $V_{DS}=3\text{V}$ ,  $10\text{mA}$
- Cost Effective Hermetic Microstrip Package
- Tape and Reel Available



### DESCRIPTION

The FSU01LG is a high performance, low noise, GaAs FET designed for PCS/PCN applications as a driver in the 2GHz band.

Eudyna stringent Quality Assurance Program assures the highest reliability and consistent performance.

### ABSOLUTE MAXIMUM RATING (Ambient Temperature $T_a=25^\circ\text{C}$ )

Item	Symbol	Condition	Rating	Unit
Drain-Source Voltage	$V_{DS}$		12.0	V
Gate-Source Voltage	$V_{GS}$		-5	V
Total Power Dissipation	$P_{tot}$	Note	375	mW
Storage Temperature	$T_{stg}$		-65 to +175	$^\circ\text{C}$
Channel Temperature	$T_{ch}$		175	$^\circ\text{C}$

Note: Mounted on  $\text{Al}_2\text{O}_3$  board (30 x 30 x 0.65mm)

Eudyna recommends the following conditions for the reliable operation of GaAs FETs:

1. The drain-source operating voltage ( $V_{DS}$ ) should not exceed 6 volts.
2. The forward and reverse gate currents should not exceed 0.7 and -0.1 mA respectively with gate resistance of  $2000\Omega$ .
3. The operating channel temperature ( $T_{ch}$ ) should not exceed  $145^\circ\text{C}$ .

### ELECTRICAL CHARACTERISTICS (Ambient Temperature $T_a=25^\circ\text{C}$ )

Item	Symbol	Test Conditions	Limit			Unit
			Min.	Typ.	Max.	
Saturated Drain Current	$I_{DSS}$	$V_{DS} = 3\text{V}$ , $V_{GS} = 0\text{V}$	35	55	75	mA
Transconductance	$g_m$	$V_{DS} = 3\text{V}$ , $I_{DS} = 27\text{mA}$	-	50	-	mS
Pinch-off Voltage	$V_p$	$V_{DS} = 3\text{V}$ , $I_{DS} = 2.7\text{mA}$	-0.7	-1.2	-1.7	V
Gate Source Breakdown Voltage	$V_{GSO}$	$I_{GS} = -2.7\mu\text{A}$	-5	-	-	V
Output Power at 1dB Gain Compression Point	$P_{1dB}$	$V_{DS} = 6\text{V}$ $I_{DS} = 40\text{mA}$	19.0	20.0	-	dBm
Power Gain at 1dB Gain Compression Point	$G_{1dB}$	$f = 2\text{GHz}$	18.0	19.0	-	dB
Noise Figure	NF	$V_{DS} = 3\text{V}$ $I_{DS} = 10\text{mA}$	-	0.55	-	dB
Associated Gain	$G_{as}$	$f = 2\text{GHz}$	-	18.5	-	dB
Thermal Resistance	$R_{th}$	Channel to Case	-	300	400	$^\circ\text{C/W}$

### AVAILABLE CASE STYLES: LG

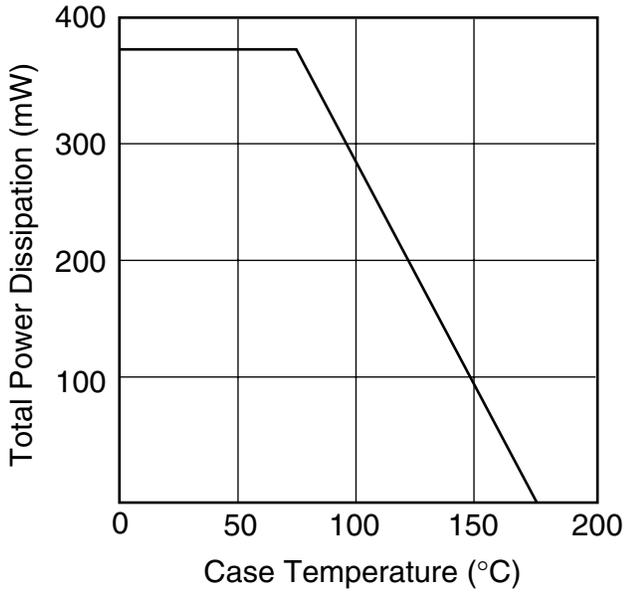
G.C.P.: Gain Compression Point

Note: The RF parameters are measured on a lot basis by sample testing at an AQL = 0.1%, Level-II inspection. Any lot failure shall be 100% retested.

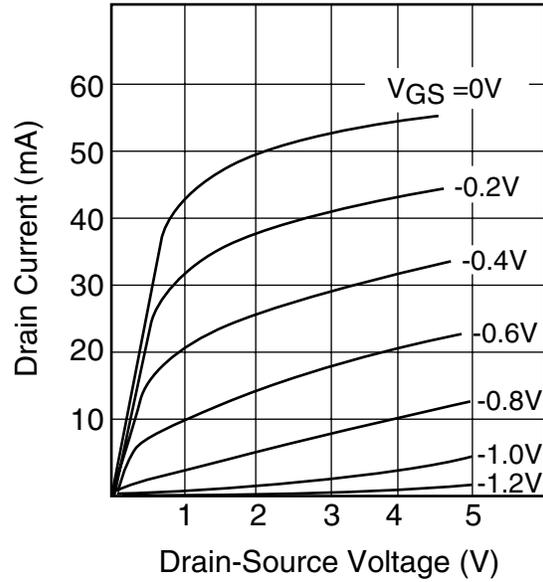
# FSU01LG

## General Purpose GaAs FET

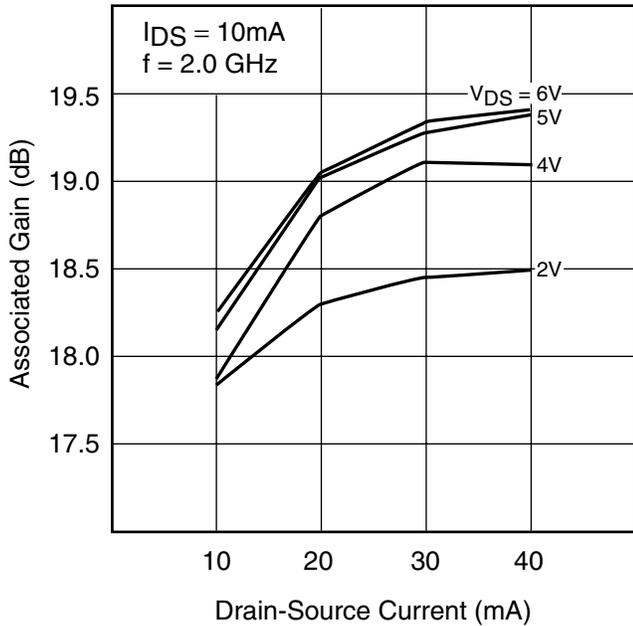
POWER DERATING CURVE



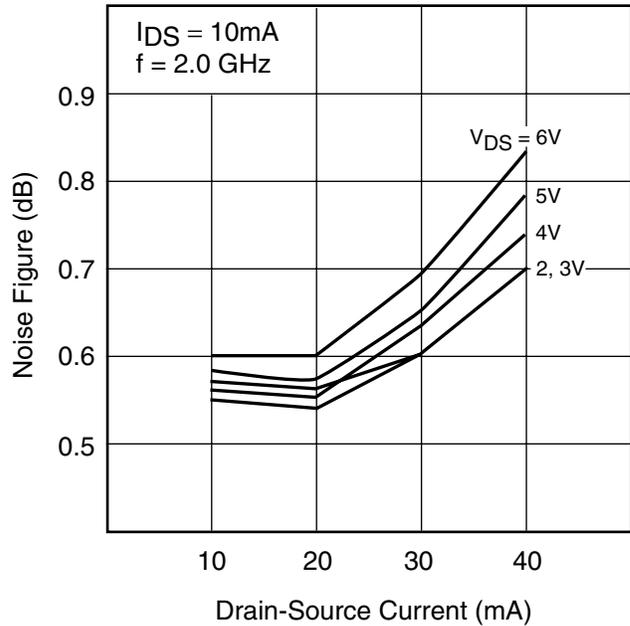
DRAIN CURRENT vs. DRAIN-SOURCE VOLTAGE

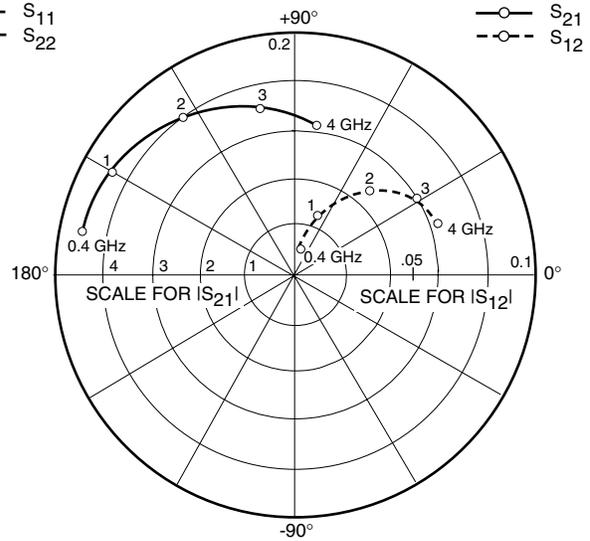
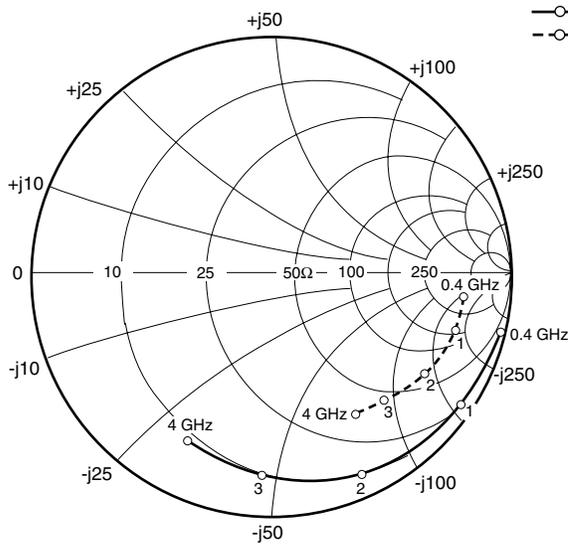


ASSOCIATED GAIN vs. DRAIN-SOURCE CURRENT



NOISE FIGURE vs. DRAIN-SOURCE CURRENT





### S-PARAMETERS

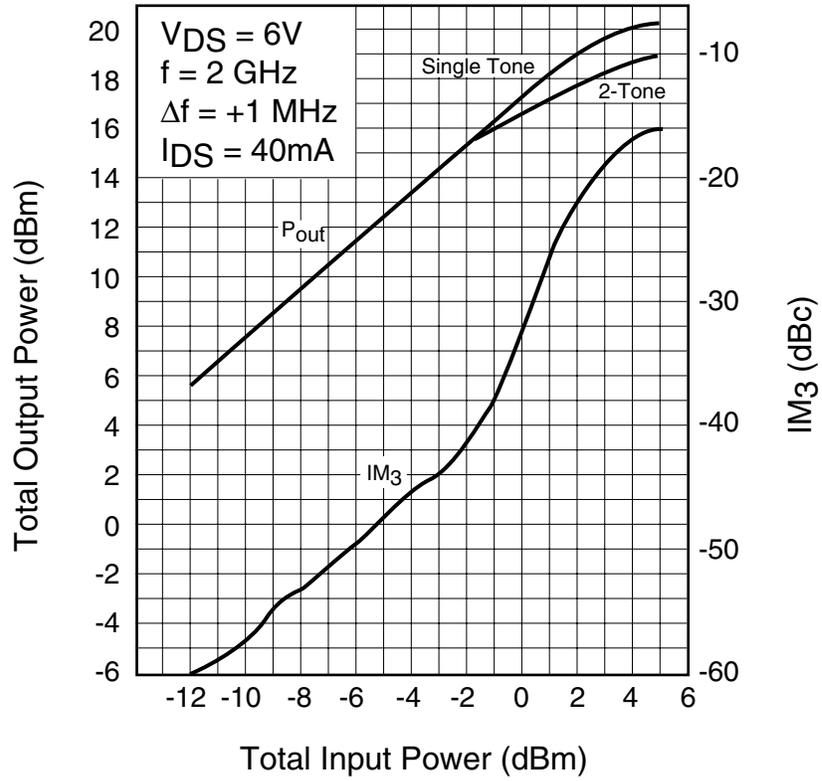
$V_{DS} = 6V, I_{DS} = 40mA$

FREQUENCY (MHZ)	S11		S21		S12		S22	
	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
400	.987	-13.8	4.507	168.3	.011	77.9	.812	-6.7
600	.985	-20.3	4.488	162.8	.016	76.2	.812	-10.0
800	.974	-27.1	4.421	157.0	.021	72.0	.807	-13.2
1000	.966	-34.1	4.367	151.3	.026	68.6	.803	-16.4
1200	.954	-40.0	4.309	146.4	.030	65.2	.793	-19.8
1400	.936	-47.0	4.212	140.5	.035	60.3	.786	-23.0
1600	.935	-53.3	4.158	135.2	.038	56.5	.778	-25.8
1800	.910	-58.7	4.037	130.8	.043	51.8	.766	-28.9
2000	.904	-65.4	3.980	125.2	.047	48.8	.761	-31.8
2200	.888	-71.0	3.885	120.7	.049	45.2	.748	-34.3
2400	.871	-77.0	3.797	115.5	.052	42.6	.739	-37.5
2600	.856	-82.5	3.696	110.9	.055	39.5	.729	-40.2
2800	.844	-88.1	3.609	106.2	.057	35.7	.716	-43.0
3000	.829	-93.3	3.511	101.9	.060	30.9	.704	-45.8
3200	.812	-98.4	3.400	97.7	.060	27.2	.692	-47.9
3400	.798	-103.1	3.323	93.8	.061	26.0	.687	-50.3
3600	.788	-107.9	3.249	89.7	.062	22.9	.681	-52.8
3800	.779	-112.6	3.176	85.6	.063	20.9	.674	-55.3
4000	.769	-117.3	3.101	81.7	.063	19.4	.668	-58.0

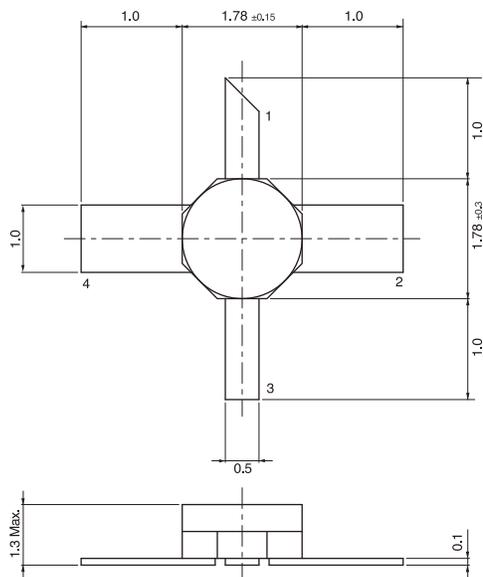
# FSU01LG

General Purpose GaAs FET

OUTPUT POWER & IM<sub>3</sub> vs. INPUT POWER



**Case Style "LG"**  
**Metal-Ceramic Package**



**Gold Plated Leads**

- 1. Gate
- 2. Source
- 3. Drain
- 4. Source

Unit: mm